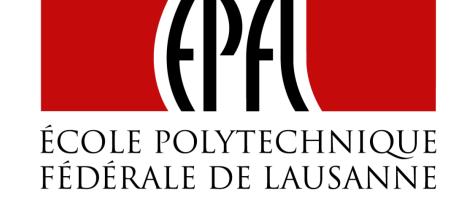


Addressing safety-criticality in optimal deployment of data-flow applications onto many-core platforms

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Motivation

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Safety-critical systems

Increasing processing demand \rightarrow Multi-/Many-Cores

Affected by scheduling, mapping and buffer sizes

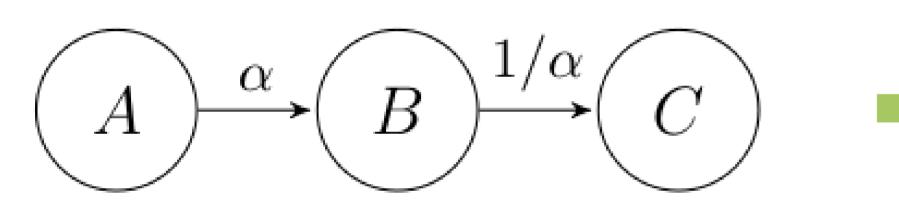
Estimating Worst-Case Execution Times (WCET) of

parallel executing tasks is challenging:

Interferences due to accessing shared resources

Application Model

- Dataflow applications as SDF + with known guarantees
- + High degree of data and task parallelism
- + Known Worst-Case Computation (WCCT) time in isolation



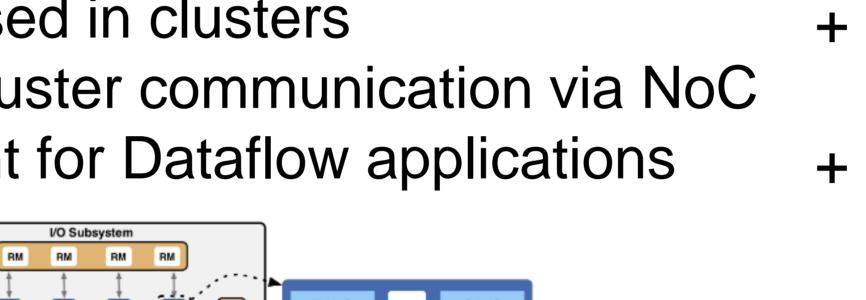
Background

Architecture Model

- + Large number of cores (>100) organised in clusters
- Intra-cluster communication via NoC

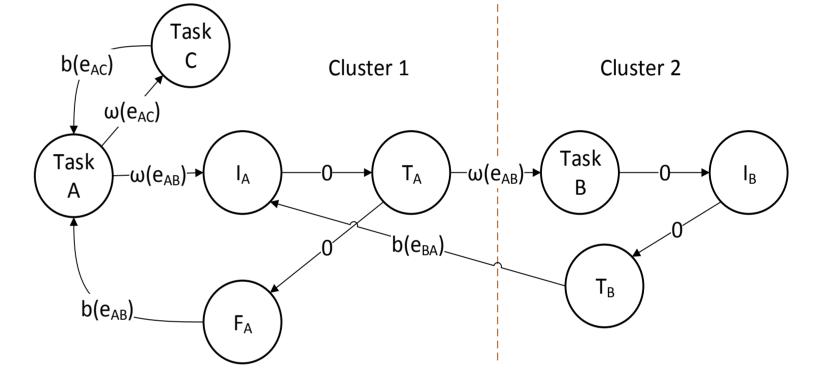
Setup:

Efficient for Dataflow applications +



Unified System Model

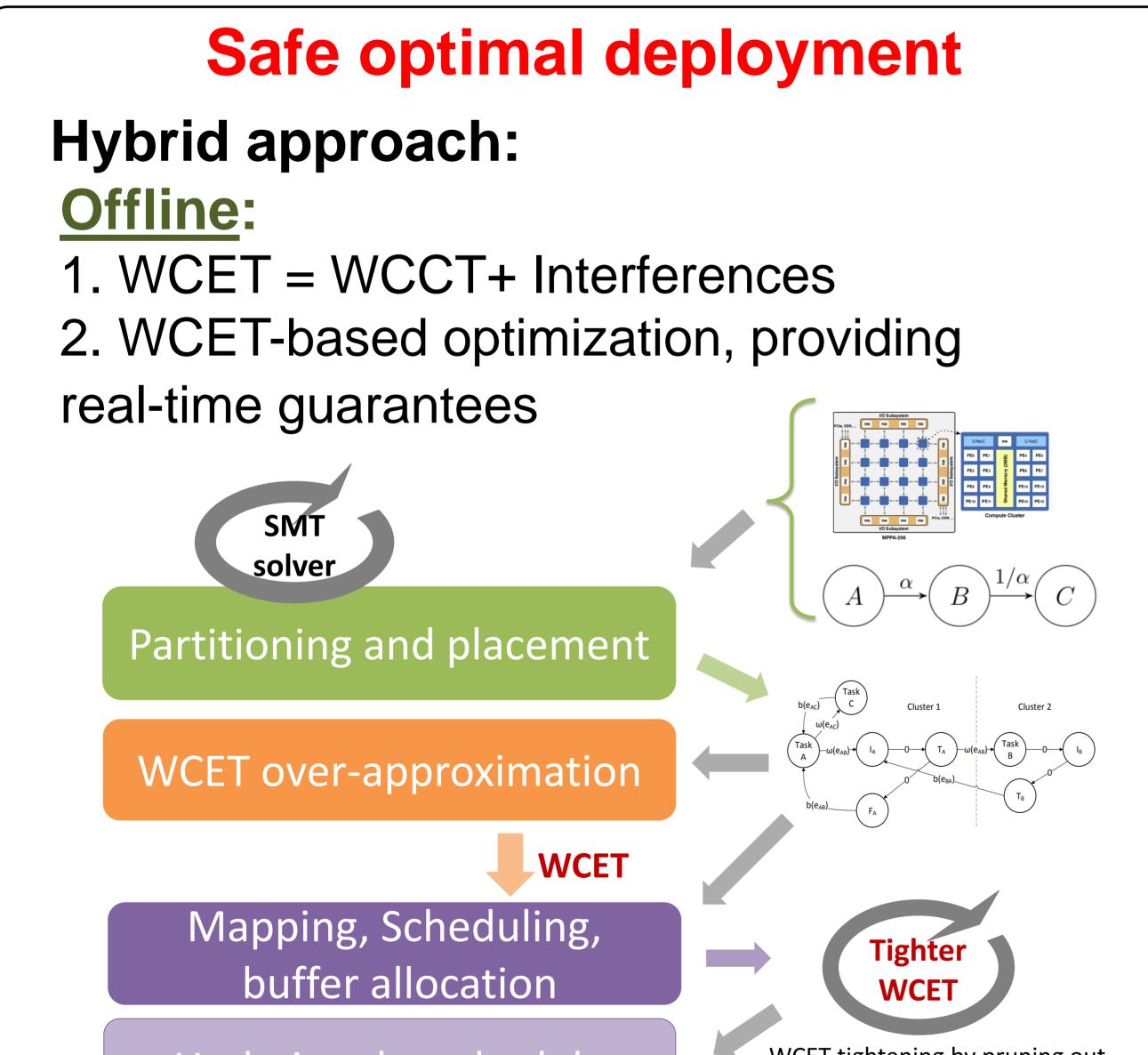
- + Derived from Application and Architecture model
- + Models both computation and communication system behavior
- + Basis for deriving WCET



Safe, optimal <u>scheduling requires knowledge of WCET</u>

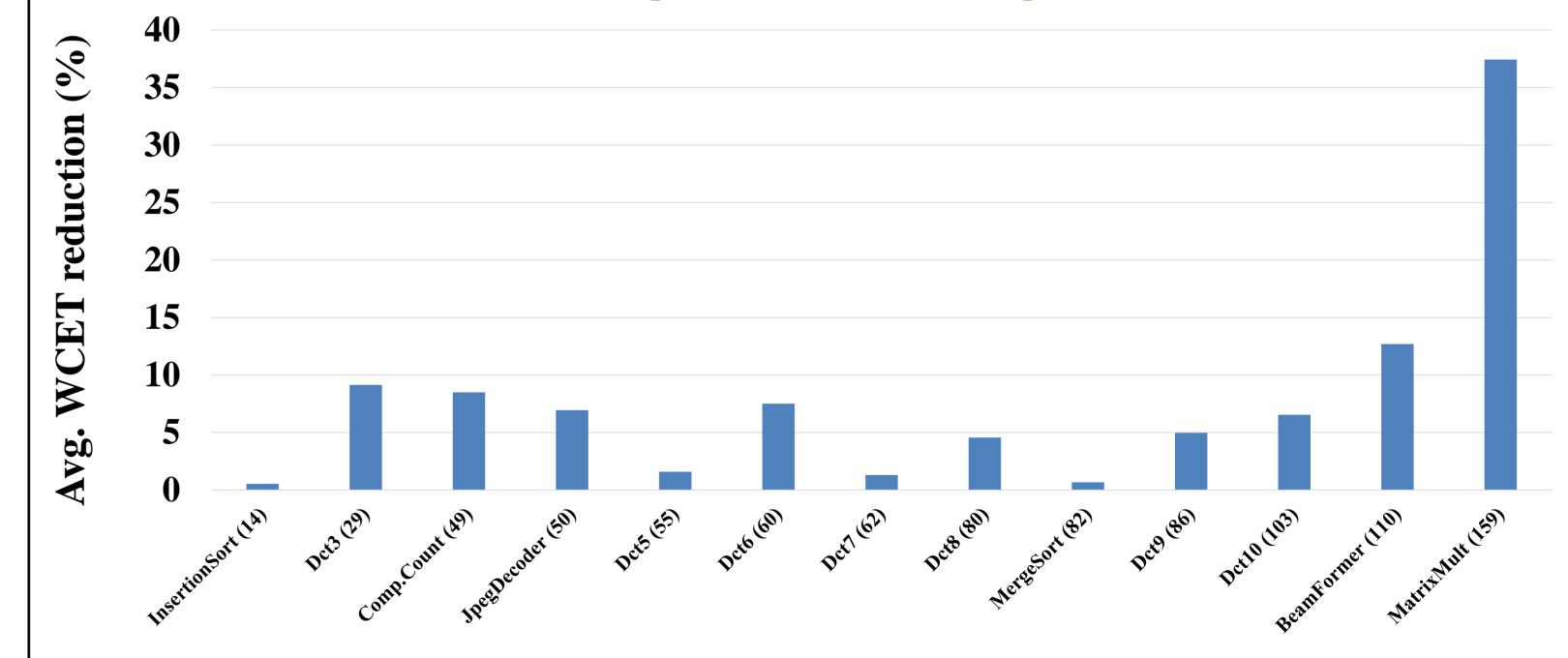
WCET

Vicious cycle \rightarrow Safe and optimal deployment is hard!



Results

- StreamIT: 18 benchmarks with profiled WCCT
- After applying our approach, deployed on Kalray MPPAlacksquare256 chip (256 cores @ 400Mhz)



WCET improvement up to 37%

WCET tightening by pruning out interferences non overlapping tasks (neither in space nor in time) Offline

Online

Updating the schedule

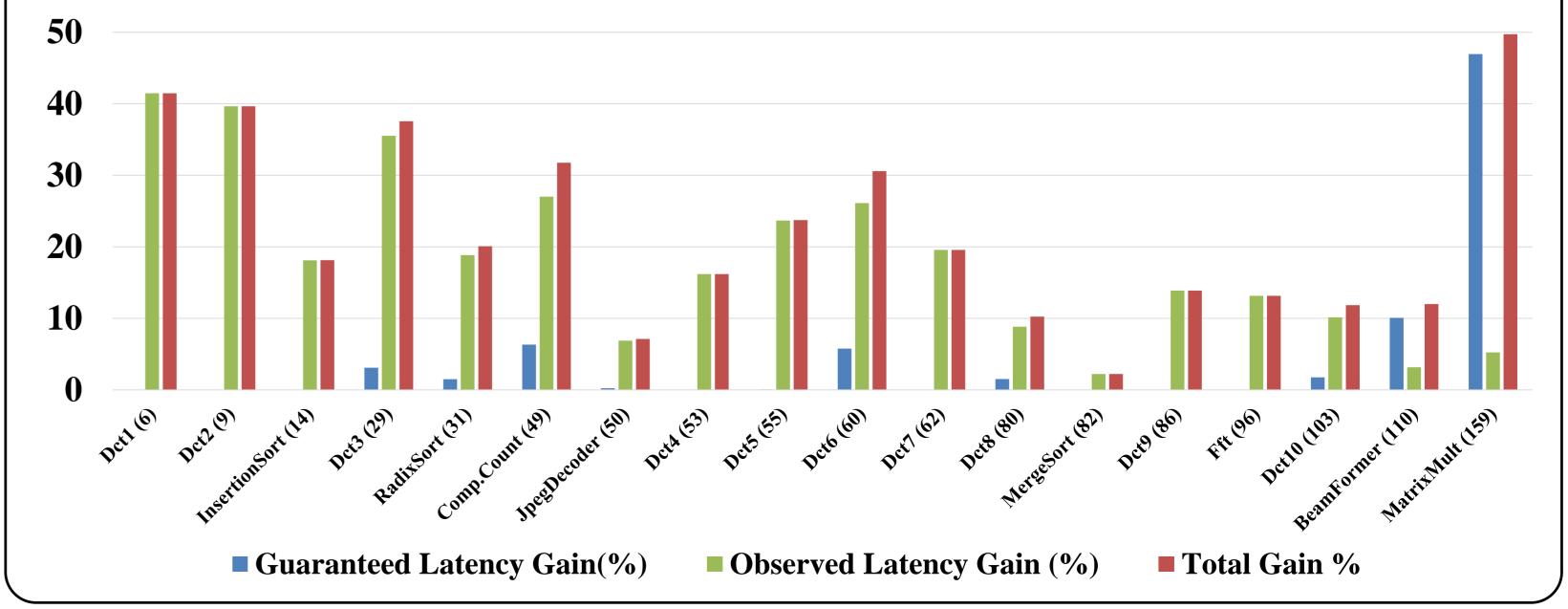
Run-time optimization

Online:

Optimizations based on actual execution times

Safe deployment without undermining performance

Offline+online latency gain up to: 49%



[1] Tendulkar, Pranav, et al. "Many-Core Scheduling of Data Parallel Applications using SMT Solvers." Digital System Design (DSD), 2014 17th Euromicro Conference on. IEEE, 2014. [2] De Dinechin, Benoît Dupont, et al. "Time-critical computing on a single-chip massively parallel processor." Design, Automation and Test in Europe Conference and Exhibition (DATE). IEEE, 2014.